CA-21 207



MILITARY TECHNICAL COLLEGE

CAIRO - EGYPT

THE USE OF COMPUTER TECHNIQUES IN SURFACECTEXTURE ASSESSMENT

H.A.NAGI.

ABSTRACT

The work represents a successful attempt of using a computer technique in surface texture assessment for metallic surfaces. A computer - Talysurf system composed of a PDP-8/L computer in connection with Talysurf 4 was employed in the analysis of surface profiles.

The performance of the Computer-Talysurf system was checked by looking into the consistency of the output reading compared with the expected values according to the loading computer program.

A loading program to the PDP-8/L computer was used to instruct the computer to register of the surface ordinates from an arbitrary datum line at certain sampling interval. A facility for changing the sampling interval and the number of registered ordinate heights was made.

A 1904 code Algol processing computer program was constructed and used for analyzing the characteristics of the measured surface profiles.

For ground surfaces, by using a sampling interval of I.219 micron and a number of ordinates equals 3000, it was found that the computed value of the surface center line average equals to yhat given by the Talysurf, and the cumulative distributions of the surface peaks and ordinates were gaussian as expected.

Finally, a picture of a surface profile obtained from the computer output compared with the surface profile obtained from the Talysurf is presented.

The operating procedure of the Computer-Talysurf system and the computer program are not included for space limitations.

Assistant Professor, Dept.of Mechanical Engineering, Al-Ashar University, Cairo, Egypt. CA-21 208

FIRST A.M.E. CONFERENCE

29-31 May 1984, Cairo

INTRODUCTION

All engineering and medical, or every day application associated with sliding or rolling elements are of tribological importance. Properties of the surfaces of such components have considerable influence on their performance efficiency.

The significance of advanced research is becomming apparent where surface systems play an important role affecting the behaviour of a physical process. In the identification and optimization of reliable systems involving surfaces, texture is the firist prerequisite for a successful accomplishment of the task in this age of automation and space flight.

We may perhaps agree that the problems in design, such as, wear, lubrication, friction, stiffness of joints, strength of parts, fatigue, paintability, accuracy of dimensional chains and kinematic trains, dynamic of machine tools, heat transfer, real contact assessment, elastohydrodynamics;.... etc, can not be satisfactorily approached without information about the surface configuration.

In manufacturing, surface quality control was limited to surface roughness as the only important feature, but now, there are many surface properties being taken into surface the consideration.

A general approach for specifying and measuring surface quality for every day purpose is needed. The texture of a part's surface often strongly influence tha ability of that part to do its job. This is true, not only when two bodies slide over each other where clearly the texture can influence the friction and wear but also in such situations as thermal contact, electrical contact, and hermitic sealing. It then becomes very important to be able to measure and describe the surface shape. The Computer-Talysurf system used in this work provides a very reliable technique in measuring and describing surface shapes.

> EXPERIMENTAL EQUIPMENT, PROCEDURE AND TECHNIQUES.

The Talysurf 4

L ...

The stylus instrument used for measuring surfaces in this work is the model 4 Talysurf surface measuring instrument produced by " RANK TAYLOR HOBSON " shown in fig. I. The Talysurf provides vertical magnifications of 500 - 10000 times and horizontal magnifications of 20 and 100. A horizontal magnification of 500 can be obtained by using an additional motor . fig. 2.

The manufacturer's specfications provides for a pick up



FIRST A.M.E. CONFERENCE

29-31 May 1984, Cairo

with a diamond stylus of a nominal tip radius of 0.0025 mm., and the stylus static force is of the order of 0.1 gm., and that is just sufficient to ensure continuous contact between the stylus and the surface being measured without causing significant damage to the surface.

The Talysurf stylus is a capacitance type one. While the stylus traverses over the surface, the capacitance changes according to the surface geometery and an electric signal is given to the PDP-8/L computer accordingly.

The PDP-8/L Computer - Talysurf System.

A PDP-8/L Computer - Talysurf system shown in fig. I., was employed in the analysis of surface profiles. It is a straightforward matter to feed the output of the Talysurf through a suitable analogue to digital conversion and sampling unit into the digital computer. The stylus and the electromechanical transducer produce the voltage analogue of the surface. The pen recorder draws the profile and at the same time a data conversion unit samples this voltage and punches it on a paper tape. The signal from the Talysurf system is averaged over intervals which can be decided upon, using units of 800 microseconds each. The signal averaged by the digital analogue converter connected to the output of the Talysurf amplifier is then stored in the core memory. The signal is varied between + I volts and is divided into a 1000 equal intervals, thus the digital output of the system varies between 000, 999. The corresponding value of each interval depends on the vertical magnification chosen. The loading program is designed in such a way that a number of samples less than 3499 can be obtained.

Checking The Performance Of The PDP-8/L Computer.

The operating procedure was followed for the following cases: I- The Talysurf was connected with the computer while the pen of the pen recorder was at position I fig. 3.

- 2- The Talysurf was connected with the computer, the pen was at position 4 fig. 3., the Talysurf vertical magnification was constant 2000 and number of digitized values was 2000. Output values were obtained for each of the sampling intervals I,2,5,I0,20,50,I00,I50,200,and 250 units,(I unit = 800 microseconds.). The results are tabulated in table I.
- 3- The Talysurf was connected with the computer, digitized values were obtained at constant sampling interval of one unit and a number of digitized values of 2000 when the pen of the recorder was at position 4 fig. 3, for each of the vertical magnifications 500,1000,2000,5000, 10000.20000.and 5000. The results are shown in table 2.

CA-21 210

position 5.

FIRCT A.M.E. CONFERENCE

29-31 Pay 1984, Cairo

Determination Of The Appropriate Sampling Interval. Three series of tests were undertaken: I- Profile measurements were taken at constant sampling interval of I.22 micrometer for 500, I000, 2000, 3000, and 3499 ordinates. 2- At a constant sampling length of 3.66 mm., tests were undertaken at sampling intervals of I.22, I.42, I.63, and 2 micrometers. 3- For a number of ordinates of 3000, tests were carried out at sampling intervals of 0.4,0.8I, I.02, I.22, I.42, and I.63 micrometers. The computed results are shown in fig.4 and in fig. 5. The Effect Of The Talysurf Stylus Traversing Speed On Parameter Values Of The Measured Surface Profiles At Constant Number Of Traverses. Three surface profiles were measured at stylus traversing speeds of 76.2, I5.24, and 3.05 mm./min. which correspond to Talysurf horizontal magnifications of 4,20, and IOO respectively. One profile was measured per traversing speed. The values of appropriate surface parameters after IO traverses are compared with those of the corresponding original surface profiles. The results are shown in table 3, and fig. 6. The Effect Of The Number Of Traverses On The Parameter Values Of The Measured Surface Profiles At Constant Traversing Speed. At a constant traversing speed of 3.05 mm./min., a surface profile was measured after leveling the Talysurf external datum relative to it and its characteristics were taken as those of the original profile. Then the characterestics of the profile were determined after 5, I0, 20, 30, and 50 traverses. Results are shown in fig. 7, and fig. 8. DISCUSSION The System Performance. All the digitized numbers were zreo when the Talysurf was connected with the computer and the pen of the recorder was at position I as in fig. 3. This is exactly what was expected because the loading program was designed to give zero reading when pen becomes at position I , 250 at position 2, 500 at position 3, 750 at position 4, and 999 at

The results shown in table I, and table 2, indicate that



FIRST A.M.E. CONFERENCE

29-31 Pay 1984, Cairo

the digitized values when the recorder pen was at position 4 fig. 3, are close to the expected value 750. The results also reveal that changing the sampling interval and the vertical magnification of the Talysurf has no effect on the digitized values relative to the pen position.

In addition, several surface profiles were measured and the computed values of the arithmetic mean deviation found to be almost equal to the values taken directly from the Talysurf. Therefore the results indicate the suitability of the PDP-8/L Computer-Talysurf system used.

The external datum should be parallel to the general direction of the profile before taking measurements. The procedure for doing this, requires the stylus to be traversed a few times across the surface at the highest traversing speed of the stylus (76.2 mm./min.). Since the number of surface profiles to be measured in surface studies is quite large. it was found necessary to investigate this matter.

Stylus Traversing Speed

It is shown in table 3, and fig. 6, that the surface traversing speed withen the practical range of speeds has no significant effect on the surface parameter values and so on the cumulative distribution of the profile ordinate heights.

Stylus Number Of Traverses.

Although the manufacturer declare that the stylus force is only sufficient to ensure continous contact between the stylus tip and the surface, it was found from fig. 7, that σ , Ra, and R₁ decrease slightly with the increase of number of traverses of the stylus, while S, and ω increase slightly.

The results are in agreement with what one would expect. Because the force acting on the asperities due the stylus force, a very small amount of deformation may occure which in turn may cause a slight reduction in Rt, Rg, and o. Such deformation is accompanied with rounding off the asperities and some peaks may well be squashed and in turn \mathcal{O} , and S may also be increased. The results also reveal that \mathcal{F} and \mathcal{O} are most sensitive to deformation effects of these kinds.

Experience has shown that leveling the datum unit of the Talysurf to the surface profile to be measured rarely requires more than IO stylus traverses across the profile. Fig. 7, shows that for IO stylus traverses, the change in the surface parameter values is withen \pm 3%, which is quite negligible. Fig. 8, shows that the cumulative distribution



FIRST A.M.E. CONFERENCE

29-31 Day 1984, Cairo

of ordinate heights of the measured surface is not significantly affected by the stylus traversing.

The Appropriate Sampling Interval.

Fig. 4, shows that the change in most of the surface parameter values at a number of ordinates greater than or equal to 2000 is negligible. It is worthy to say that at constant sampling interval, the larger the digitized number of ordinate heights, the bigger the length of the studied surface profile, the closer the computed parameter values to the actual values of the surface.

Fig. 5, shows that the graphs of the parameter values of the measured surface profile with the change in the sampling interval at constant sampling length intersect with their corresponding ones at constant number of ordinates 3000 at sampling intervals ranging from I.I to I.35 micron of which I.22 micron is an average value.

The above technique was used for computing the R and R of a test specimen using 3000 ordinates and I.22 micron as sampling interval, results were very close to those stated; by the national laboratry in the U.K.

Fig. 9, shows that the reproduced profile trace by the system is quite satisfactory representation of the profile produced by the Talysurf.

CONCLUSION

- I- The PDP-8/L Computer-Talysurf system is reliable for metallic surfaces studies.
- 2- A number of ordinates equals to 3000 and a sampling interval of I.22 micron are suitable for surface texture assessments.
- 3- The Talysurf stylus traversing speed has no significant effect on surface characterestics.
- 4- For practical applications, the stylus traversing has no significant effect on the characterestics of the measured profiles.

CA-21 2L3

Г

REFERENCES

- I. Archard, J.F., Hunt, R.T. and onions, R.A., "Stylus Profilometry and Analysis Of The Contact Of Rough Surfaces", Proceedings Of The IUTAM Sympsium On The Mechanics Of The Contact Of Deformable Bodies. Delft University Press(1975).
 - 2. B.S.I., "Assessment Of Surface Texture".British Standard Institution, BS II34.(1972) 3. Ebrle, O.A., "Graphical Method For Statistical Assessment

they lost, Calls

- Of Surface Roughness Comparison Specimens", Proc. I. Mech, Eng. Vol. 182, Part 3K, Properties And Metrology Of surfaces. P.368.(1967 - 68)
- 4. Greenwood, J.A., and Trip, J.H., "The Contact Of Nominally Flat Surfaces", Proc.Instn.Mech.Engineers. Vol.185, P 625, (1970)
- 5. Halling, J., "The Specification Of Surface Quality -
- Quo Vadis?", The Production Engineers. (1972) 6. Myers, N.O., "Characterization Of Surface Roughness".
- Wear, 5, P. 182. (1962) 7. Thomas, R.T., "Recent Advances In The Measurement And Analysis Of Surface Microgeometry". Wear, Vol. 33, P. 205. (1975)
- 8. Whitehouse, D.J., "The Measurement And Analysis Of Surfaces". Tribology International. (1974)
 - 9. Williamson, J.B.P., Pullen, J.P., and Hunt, R.T., "The Shape Of Solid Surfaces". ASME Surface Mechanics. (1970)

NOMENCLATURE

Height i Sampling	from datum line. z interval.	micron.
Percente Arithme Maximum Average	ige of ordinates tic mean deviation. peak to valley height. spacing of asperities.	micron. micron. micron.

1+

1_

P 5

h 1 p R 8 R st

	r				
				29-31 Ma	ny 1984, Cairo
80 CB (PA 381 AB) 386 3				ی میں میں بائی میں اور اور میں	
T	able I.	The influ on the ou	lence of ltput pun	sampling i ched value	nterval s at
		constant vertical	no of or magnific	dinates an ation.	d
ampling pu nterval va (units)	unched alue	Sampling interval (units)	Punched value	Sampling interval (units)	Punched value
I 7	754	20	756	I50	755
2 7	770	50	770	200	769
5 7	756	I00	753	250	758
IO 7	775				
io.of digiti lests were d same order s	carried as shown Table 2.	out three The infl magnific constant	times, t uence of ation on no.of se	the results changing t the output imples and	were of the the vertical t values at sampling
io.of digiti lests were d same order s	Lzed val carried as shown Table 2.	The infl magnific constant interval	times, t uence of ation on no.of se	the results changing t the output imples and	were of the the vertical t values at sampling
Vertical mag	rable 2.	out three out three The infl magnific constant interval	times, t uence of ation on no.of se erage of	the results changing t the output imples and digitized	were of the the vertical t values at sampling values
Vertical mag	rable 2.	tion Av	times, t uence of ation on no.of se erage of 75	the results changing to the output amples and digitized	were of th the vertical values at sampling values
Vertical mag	rable 2.	out three out three a tion Av	times, t uence of ation on no.of se erage of 75 74	the results changing to the output imples and digitized	were of the the vertical t values at sampling values
Vertical mag	rable 2. gnificat	tion Av	times, t uence of ation on no.of se erage of 75 74 74	changing to changing to the output imples and digitized	were of the the vertical t values at sampling values
Vertical mag	rable 2. gnificat	ues=2000 out three The infl magnific constant interval	times, t uence of ation on no.of se erage of 74 74 74 74	the results changing to the output imples and digitized 59 44 44 51	were of the the vertical t values at sampling values
Vertical mag	zed val carried as shown Table 2. gnificat 500 1000 2000 5000	tion Av	times, t uence of ation on no.of se erage of 75 74 74 74 75	changing to the output imples and digitized	were of the the vertical t values at sampling values
Vertical mag	zed val carried as shown Table 2. mificat 500 1000 2000 5000 10000 20000	tion Av	times, t uence of ation on no.of se erage of 74 74 74 74 75 74 74 74 75 75 74 75 75 74 75 75 75 75 75 75 75 75 75	changing to the output imples and digitized 59 44 44 51 57 55 57	were of the the vertical t values at sampling values

L.

CA-21	2L3

Г

REFERENCES

- I. Archard, J.F., Hunt, R.T. and onions, R.A., "Stylus Profilometry and Analysis Of The Contact Of Rough . Surfaces", Proceedings Of The IUTAM Sympsium On The Mechanics Of The Contact Of Deformable Bodies. Delft University Press(1975).
 - 2. B.S.I., "Assessment Of Surface Texture".British Standard Institution, BS II34.(1972) 3. Ebrle, O.A., "Graphical Method For Statistical Assessment
 - Of Surface Roughness Comparison Specimens", Proc. I. Mech. Eng. Vol. 182, Part 3K, Properties And Metrology Of surfaces. P.368.(1967 - 68)

Mr-Al Mary 1984, Caller

- 4. Greenwood, J.A., and Trip, J.H., "The Contact Of Nominally Flat Surfaces", Proc.Instn.Mech.Engineers. Vol.185, P 625. (1970)
- 5. Halling, J., "The Specification Of Surface Quality -
- Quo Vadis?", The Production Engineers. (1972) 6. Myers, N.O., "Characterization Of Surface Roughness".
- Wear, 5, P. 182. (1962) 7. Thomas, R.T., "Recent Advances In The Measurement And Analysis Of Surface Microgeometry". Wear, Vol. 33, P. 205. (1975)
- 8. Whitehouse, D.J., "The Measurement And Analysis Of Surfaces". Tribology International. (1974)
 - 9. Williamson, J.B.P., Pullen, J.P., and Hunt, R.T., "The Shape Of Solid Surfaces". ASME Surface Mechanics. (1970)

NOMENCLATURE

Height from datum line. Sampling interval.	micron. micron.
Percentage of ordinates Arithmetic mean deviation. Maximum peak to valley height. Average spacing of asperities.	micron. micron. micron.

1+ 1 . -

L

P

h 1 p R 8 St R

	Table I	. The infl on the o constant vertical	uence of utput pun no of or magnific	sampling i ched value dinates an ation.	nterval s at d
ampling nterval (units)	punched value	Sampling interval (units)	Punched value	Sampling interval (units)	Punched value
I	754	20	756	I50	7 55
2	770	50	770	200	769
5	756	IOO	753	250	758
IO	775				
vertical lo.of dig lests wer same orde	magnifica sitized va re carried er as show Table 2	. The infl magnific constant	e times, t luence of cation on t no.of st	the results changing f the output amples and	the vertiant sampling
ertical o.of dig ests wer ame orde	magnifica itized va re carried er as show Table 2 magnifics	tion=2000 lues=2000 out three m. constant interval	e times, luence of cation on t no.of sa l	the results changing f the output amples and digitized	the vertice t values a sampling values
Vertical	magnifica itized va re carried r as show Table 2 magnifics 500	tion=2000 lues=2000 out three m. 2. The infl magnific constant interval	e times, luence of cation on t no.of sa verage of 7	the results changing f the output amples and digitized	the vertiant the vertiant t values a sampling values
Vertical No.of dig Nests wer Same orde	magnifica pitized va re carried r as show Table 2 magnifica 500 I000	tion=2000 lues=2000 out three m. 2. The infl magnific constant interval	e times, luence of cation on t no.of sa verage of 7 7	the results changing f the output amples and digitized 59 44	the vertice t values a sampling values
Vertical No.of dig Nests wer Same orde	magnifica pitized va re carried r as show Table 2 magnifics 500 1000 2000	tion=2000 lues=2000 out three m. constant interval	e times, luence of cation on t no.of sa verage of 7 7 7 7	the results changing f the output amples and digitized 59 44	the vertice to values a sampling values
Vertical Sests were same orde	magnifica gitized va re carried r as show Table 2 magnifica 500 1000 2000 5000	tion=2000 lues=2000 out three m. 2. The infl magnific constant interval	e times, luence of cation on t no.of sa verage of 7 7 7 7 7 7 7	the results changing f the output amples and digitized 59 44 44 61	the vertice the vertice t values a sampling values
Vertical	magnifica re carried r as show Table 2 magnifica 500 1000 2000 5000 10000	tion=2000 lues=2000 out three m. constant interval	e times, luence of cation on t no.of sa verage of 7 7 7 7 7 7 7 7	the results changing f the output amples and digitized 59 44 44 61 57	the vertice twalues sampling values
Vertical No.of dig Tests wer same orde	magnifica re carried r as show Table 2 magnifica 500 1000 2000 1000 2000 10000 2000	tion=2000 lues=2000 out three m. 2. The infl magnific constant interval	e times, luence of cation on t no.of sa verage of 7 7 7 7 7 7 7 7 7 7 7	the results changing f the output amples and digitized 59 44 44 61 57 55	the vertice t values sampling values

Talysurf stylus was at position 4 Fig. 3. Tests were carried out 3 times, results were of the same order.

L.

CA-21 21.5

Г

L ...

6

FIRST A.M.E. CONFERENCE

29-31 May 1984, Cairo

Table 3. The effect of the Talysurf stylus traversing speed on surface parameter values.

Traversing speed Parameter	76.2 mm./min. D%	15.24 mm./min. D%	3.05 mm./min. D%
Max peak to valley height.	0.39	0.44	I.88
Average spacing of asperit	ies0.97	2.89	-I.69
Arithmetic mean deviation.	-0.09	2.17	I.03
Standard deviation of peak	3.6	7.87	0.03
Average radius of peak curvatures.	-9.17	0.82	I.49
Mean positive slope at mean line.	3:38	0.42	4.59
Mean negative slope at mean line.	IO.46	-7.33	-0.4

: D% = Deviation percentage from original profile parameter values.

Vertical magnification = 5000.

CA-21 216



ME THE REPORTED FOR A STREET

2

Elg. L. .ne mu~8/1 Computer - Inlystand s. Lat.

CA-21 217 - 35

i 1

- 4



THE ADDITIONAL DRIVE MOTOR CONNECTED

Fig. 2. The Additional Shave motor formation .

CA-21	218
-------	-----



THE RECORDER OF THE TALYSURF

2

FiG. 3. The Record of The Luysur.



Fig. 4 THE CHANGE IN SOME SURFACE PARAMETER VALUES WITH THE CHANGE IN THE NUMBER



1

SURFACE PARAMETER VALUES FIG. 5. THE CHANGE IN SOME THE CHANGE IN THE SAMPLING INTERVAL. WITH

CA-21 220









MANAMAN MAN A COMPARISON BETWEEN A PROFILE TRACE OF A GROUND SURFACE PRODUCED BY THE TALYSURF Fig.9. AND THAT ONE REPRODUCED FROM THE OUTPUT

LIST OF AUTHORS

ABDEL-AZIM , O. - El-Minia University ABDEL-AZIZ , S. - Military Technical College ABDEL-BARR , S.Z. -Ain Shams University ABDEL-FATAH, M.R. - Military Technical College ABDEL-FATAH, A. - El-Mansoura University ABDEL-GHANY, A.A.- Airforces ABDEL-LATIF, A.K.- King Abdulaziz University, Soudia ABDEL-MOATY, A. - Cairo University ABDEL-MOHSEN, A.S.- Military Technical College ABDEL-MONEIM, M. - Suez Canal University ABDEL-MONEM, M. - Engineering Organization ABDEL-RAHMAN, M. -El-Minia University ABDEL-RAOUF, H. - King Abdulaziz University, Saudia ABDEL-SALAM, M.S.-CODSE ABDOU, M.A. - Al-Azhar University ABDULLA, Y.A.G. - Gulf Polytechnic, Bahrain ABOU E1-ENENE, A.M. - E1-Menoufia University ABOU El-NOUR, A. - Zagazig Univeristy ABOU El-SEOUD, S.A. - El-Minia Univeristy ABU-ZEID, O.A. - Cairo University AFFIA, N.M. - Ain Shams University AFIFI, M.Y. - Ain Shams University AHMED, O.M. - Assiut University ASFOUR, H.M. - El-Minia University ASHOUR, N.M. - Helwan University ATTIA, A.Y. - Ain Shams University Badawy, E.M. - Alexandria University BADRAN, F.M. - Assiut University BAHGAT, B.M. - Cairo University BAHI, S. - Al-Azhar University BARAKAT, A.G. - Military Technical College BASSIOUNI, A.S. - Military Technical College BEDEWY, M.K. - Cairo University BEKHET, N. - Helwan University BOIVIN, M. - Institut National des Sciences Appliqueés de lyon, France BOSE, M.S.C. - Indian Institute of Technology, India

COOKSON, R.A. - Cranfield Institute of Technology, U.K. DARWISH, A.H. - Al-Azhar University EBIED, S.J. - Ain Shams University EISSA, M. - El-Menoufia University ELRABY, M.E. - Cairo University EL-BAHI, A.M. - Arab Organization for Industry EL-BAKRY, M. - National Research Centre EL-DARDIRY, M.A. - King Abdulaziz University, Saudia EL-GAMMAL, M.M. - Alexandria University EL-GEMAE, S.H. - Al-Azhar University EL-GENDY, M. - El-Menoufia University EL-HADDAD, M.H. - Cairo University EL-HIFNAWI, N.N. - Technical Research Centre EL-KADEEM, M.A. - Alexandria University EL-KHABEERY, M.M. - El-Menoufia University EL-KOTB, M.M. - Cairo University EL-LAITHY, H. - Air Forces EL-MADDAH, M.M. - Military Technical College EL-MAHALLAWY, N. - Ain Shams University EL-MIDANY, T.T. - King Abdulaziz University - Saudia EL-MOWAFY, S.A. - Vehicle Department EL-NAGGAR, M. - Military Technical College EL-NOMROSSY, M.M. - Military Technical College EL-SAWY, A. - Cairo University EL-SAYED, M. - El-Mansoura University EL-SEBAI, N.A. - Military Technical College EL-SHAKERY, S.A. - El-Menoufia University EL-SHERBINY, M. - King Abdulaziz University, Saudia EL-SHERIF, F. - Helwan University EL-SIBAIE, A.M. - Ain Shams University EL-SOALY, E.E. - Military Technical College EL-SOMOKHLY, S.Y. - Suez Canal University EL-ZAFRANY, A. - Cranfield Institute of Technology ESSAWY, M.E. - Military Technical College FAKHRO, S.Q. - Gulf Polytechnic, Bahrain FARGHALY, S.H. - Helwan University

FARID, M.S. - Cario University FAT-HALLA , N. - AL-Azhar University FATTAH, A.A. El-Mansoura University FATTOUH, M. - El-Menoufia University FEIJO, F. - Central Florida University, U.S.A. FOUAD, M.A. - Al-Azhar University GABALLA, M.A. - Assiut University GABER, A. - Military Technical College GABRA, M.S. - Military Technical College GADALLAH, N. - Military Technical College GHABRIAL, S.R. - Ain Shams University GINDY, A.S. - Cairo University GOMAA, T. - Armed Forces HAMMOUDA, M.M. - Al-Azhar University HANNA, H.A. - Zagazig University HASSAN, G.A. - Cairo University HASSAN, S.A. - Military Technical College HEGAZY, A. - Helwan University HEWEIDY, M.S. - El-Menoufia University IBRAHIM, G.Y. - Cairo University IBRAHIM, M.F.E. - Military Technical College IMAM, E.I. - Military Technical College ISMAIL, M.K. - Military Technical College ISMAIL, M. - Al-Azhar University KAMEL, H.M. - Cairo Oil Refining Company KASSAB, M.E. - Arab Organization for Industry KASSEM, S.A. - Cairo University KHALIFA, S.E. - Military Technical College KHEDRE, O.M. - El Menoufia University KHORSHID, S. - Cairo University KOSSA, S.S. - Military Technical College KOTB, A.M. - Technical Research Centre KOUSSA, S.S. - Cairo University LOTFY, A.H. - Military Technical College MAHER, A. - Military Technical College MAHMOUD, O.H.M. - Alexandria University MAJID, M.A. - Gulf Polytechnic, Bahrain

MAKROUM, H.A. - Helwan University MEGAHED, M.M. - King Abdulaziz University - Saudia METWALLI, S.M. - Kuwait University, Kuwait METWALLY, H.M. - Alexandria University METWALLY, M. - Gulf Polytechnic, Bahrain MIKHAIEL, S.N. - Cairo University MILLER, K.J. - Sheffield University, U.K. MOHAMED, A.S. - Zagazig University MOHAMMED, M.A.S. - Military Technical College MOHAMMED, S. - Military Technical College MOKHTAR, M.O. - Cairo University MOMEH, Z. - Military Technical College MORSY, A.A. - Al-Azhar University MOSTAFA, M.M. - Military Technical College MOUSSA, A.M. - Helwan University MOUSSAD, S.A. - Alexandria University MOUSTAFA, S.M. - El-Minia University NAGA, S.A.R. - Zagazig University NAGI, H.A. - Al- Azhar University NASSER, A.A. - El-Menoufia University NASSER, M.A. - El-Menoufia University NEGM, M.I. - Al-Azhar University NOSSEIR, T.A. - Ain Shams University OSMAN, H.M. - El-Minia University OSMAN, M.O.M. - Cairo University OSMAN, M.S. - Military Tecnical College RABIE, G. - Cairo University RABIE, M.G. - Military Research Authority RAGAB, A.A. - Kuwait University, Kuwait RAJAIAH, k. - Indian Institute of Technology, India RASHED, A.F. - King Abdulaziz University, Saudia RASHED, F.M.E. -Helwan University REFAI, M. - Al-Azhar University ROUSHDY, E.H. - Qatar University, Qatar SAFWAT, H.M. - Alexandia University SALEH, I. - Military Technical College SALEH, S.M. - Military Technical College

SALEM, E.A. - Alexandria University SALEM, F. - Cairo University SALEM, H. - Cairo University SALLAM, T.M. - Alexandria University SALMAN, F.K. - Alexandria University SATHIANATHAN, S.K. - Cranfield Institue of Technology, U.K. SAYED, A.S. - Military Technical College SCHLACK, A.L. - Wisconsin - Madison University, U.S.A. SERAGE, S.M. - El-Menoufia University SHAABAN, S.M. - Military Tecnical College SHAMLOUL, M.M. - Zagazig University SHAWKY, A.A. - Military Technical College SHEHA, G.M. - El-Menoufia University SHEHATA, S.A. - Zagazig University SHOUKRY, S.N. - Helwan University SHOULA, O.Y. - Naval Aichitecture SOLIMAN, M.H.M. - Alexandria University SORENSEN, K.V. - Bruel & Kjaer, Denmark TAHA, M.A. - Ain Shams University TAKLA, M.R. - Cairo University THORNLEY, R.H. - Aston University, U.K. TOLBAH, F.A. - Ain Shams University WAGDI, M.N. - Suez Canal University YOUNES, Y.K. - Helwan University ZAGHLOOL, S.A. - Ain Shams University ZAKI, M. - Al-Azhar University ZAKZOUK, M.E.I. - Helwan University ZIADA, H.H. - King Abdulaziz University, Saudia KAMAL E1-DIN, H - Oklahoma State University, U.S.A.

